

Each year, VTS proudly presents the Best Paper Award to the author(s) of the most outstanding paper from those presented at the previous year's symposium. The candidates for this honor are initially selected based solely on the numerical ratings of the reviewers and symposium attendees, as recorded on the review forms and the session rating cards. The Best Paper Award Judges then carefully review the candidate papers as published in the proceedings. The judges provide numerical scores and comments for each candidate paper. The scores and comments are compiled to select the best paper.

The paper selected by the VTS 2005 Best Paper Award Judges for the Best Paper Award is:

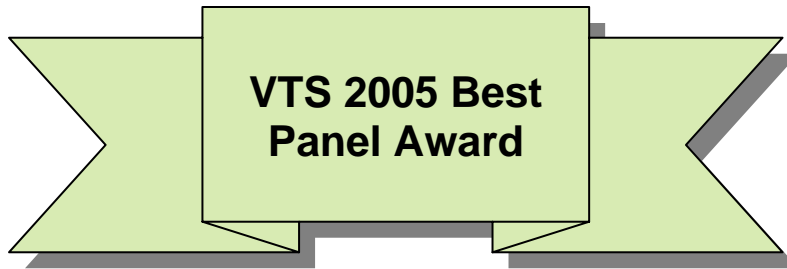
"At-Speed Transition Fault Testing With Low Speed Scan Enable"
by Nisar Ahmed, C. P. Ravikumar, Mohammad Tehranipoor, and Jim Plusquellic

Congratulations to the winners!

The VTS 2005 Best Paper Award Judges are listed below. VTS extends special thanks to these individuals for reviewing the papers and offering invaluable comments.

Vishwani Agrawal, Auburn University
Joan Figueras, Universitat Politecnica de Catalunya
Peter Maxwell, Avago Technologies
Janusz Rajski, Mentor Graphics
Stephen Sunter, LogicVision
Hans-Joachim Wunderlich, University of Stuttgart

Special thanks also to Sudhakar M. Reddy, University of Iowa, USA, who coordinated the selection process.



Each year, VTS recognizes the organizers and participants of the best panel at the pervious year's symposium. The selection is based entirely on audience feedback, as recorded on the attendee feedback forms.

For VTS 2005, the Best Panel Award goes to:

Panel 13C: Analog TRP - Is Convergence on the Horizon?

Organizers: D. Conti - IBM; A. Khoche - Agilent; D. Wheater - IBM

Moderator: G. Roberts - DFT Microsystems

Panelists:

P. Berndt - Cypress

J.-L. Carbone - ST Microelectronics

J. Mclaughlin - Agilent

M. Mowji - LTX Corp

P. Variyam - Texas Instruments



Each year, VTS recognizes the organizers and presenters of the best Innovative Practices Session at the previous year's symposium. The selection is based entirely on audience feedback, as recorded on the attendee feedback forms.

For VTS 2005, the Best Innovative Practices Session Award goes to:

Session 11C: Delay Fault Testing - Industrial Case Studies

Organizer: A.K. Majhi, Philips
Moderator: A. Singh - Auburn Univ.

Presenters:
A.K. Majhi, G. Gronthoud, F. Bowen and S. Eichenberger - Philips
V.B. Jayaram, S. Goel, R.A. Parekhji and K. Butler - Texas Instruments
R. Raina - Freescale Semiconductor